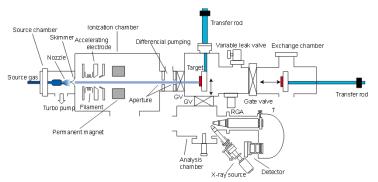


## Fundamental Study of Gas Cluster Interaction with Thin Films and Materials used in Semiconductor Processing (Task ID:2077.001)

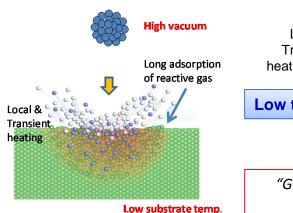


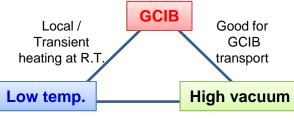
Task Leaders: Noriaki Toyoda (Univ. of Hyogo) Science area: Nano-manufacturing Science

- Gas cluster ion beam (GCIB) is a directional energetic chemical beam technique, and it enhances chemical reactions owing to dense energy deposition. However, reaction mechanisms are not clearly understood.
- Focus of this task is more fundamental understanding of GCIB reaction mechanisms



In-situ XPS-GCIB system for surface reaction study



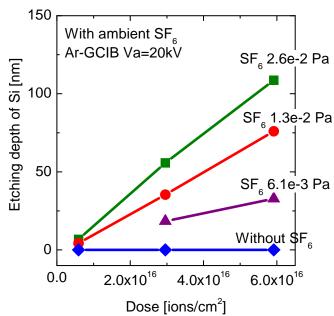


Long time adsorption of reactive gas

→ Small supply of reactive gas

"GCIB" – "Low temp." – "High vacuum" These three issues can co-exist.

- Energy/atom(molecule) dominates chemical reactions, which suddenly increase above 1eV/molecule.
- Since GCIB enhances chemical reactions owing to its dense energy deposition, reactions between background gas and target are enhanced during GCIB irradiation.
- By intentional introduction of reactive gas as background gas, new etching or film deposition process are expected.



Etching enhancement on Si with Ar-GCIB irradiation with SF<sub>6</sub> background gas.

